

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10511456	PAYNE, PATRICK
	Examiner	Art Unit
	Kim, Edward J	2109

SEARCHED

Class	Subclass	Date	Examiner
709	201-253		Edward J Kim
379	200-207		Edward J Kim
455	1-575.9		Edward J Kim

SEARCH NOTES

Search Notes	Date	Examiner
Also searched the Derwent, JPO, EPO, and IBM databases		Edward J Kim
Also conducted inventor search on Patrick Payne		Edward J Kim

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner